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Examiner

Christopher R. Lamb

Applicant(s)/Patent under Reexamination

CHEN, CHIH-YUAN

Art Unit

2627

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
Consulted SPE Wayne Young regarding field of search	7/6/2006	CRL
EAST Search	7/6/2006	CRL